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Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	20
Number of Macrocells	320
Number of Gates	6000
Number of I/O	132
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	208-BFQFP Exposed Pad
Supplier Device Package	208-RQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm9320arc208-10

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

General Description

The MAX 9000 family of in-system-programmable, high-density, high-performance EPLDs is based on Altera's third-generation MAX architecture. Fabricated on an advanced CMOS technology, the EEPROM-based MAX 9000 family provides 6,000 to 12,000 usable gates, pin-to-pin delays as fast as 10 ns, and counter speeds of up to 144 MHz. The -10 speed grade of the MAX 9000 family is compliant with the *PCI Local Bus Specification, Revision 2.2.* Table 3 shows the speed grades available for MAX 9000 devices.

Table 3. MAX 9000 Speed Grade Availability						
Device		Speed Grade				
	-10	-15	-20			
EPM9320		✓	✓			
EPM9320A	✓					
EPM9400		✓	✓			
EPM9480		✓	✓			
EPM9560		✓	✓			
EPM9560A	✓					

Table 4 shows the performance of MAX 9000 devices for typical functions.

Table 4. MAX 9000 Performance Note (1)									
Application	Macrocells Used	Macrocells Used Speed Grade Units							
		-10	-15	-20					
16-bit loadable counter	16	144	118	100	MHz				
16-bit up/down counter	16	144	118	100	MHz				
16-bit prescaled counter	16	144	118	100	MHz				
16-bit address decode	1	5.6 (10)	7.9 (15)	10 (20)	ns				
16-to-1 multiplexer	1	7.7 (12.1)	10.9 (18)	16 (26)	ns				

Note:

(1) Internal logic array block (LAB) performance is shown. Numbers in parentheses show external delays from row input pin to row I/O pin.

The MAX 9000 architecture supports high-density integration of system-level logic functions. It easily integrates multiple programmable logic devices ranging from PALs, GALs, and 22V10s to field-programmable gate array (FPGA) devices and EPLDs.

The MAX 9000 family is supported by Altera's MAX+PLUS II development system, a single, integrated software package that offers schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The MAX+PLUS II software provides EDIF 2 0 0 and 3 0 0, LPM, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. The MAX+PLUS II software runs on Windows-based PCs as well as Sun SPARCstation, HP 9000 Series 700/800, and IBM RISC System/6000 workstations.



For more information on development tools, see the MAX+PLUS II Programmable Logic Development System & Software Data Sheet.

Functional Description

MAX 9000 devices use a third-generation MAX architecture that yields both high performance and a high degree of utilization for most applications. The MAX 9000 architecture includes the following elements:

- Logic array blocks
- Macrocells
- Expander product terms (shareable and parallel)
- FastTrack Interconnect
- Dedicated inputs
- I/O cells

Figure 1 shows a block diagram of the MAX 9000 architecture.

Figure 1. MAX 9000 Device Block Diagram

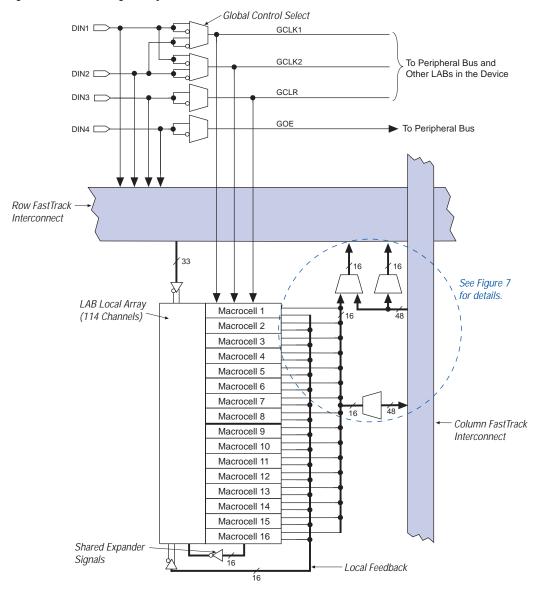
Logic Array Blocks

The MAX 9000 architecture is based on linking high-performance, flexible logic array modules called logic array blocks (LABs). LABs consist of 16-macrocell arrays that are fed by the LAB local array, as shown in Figure 2 on page 7. Multiple LABs are linked together via the FastTrack Interconnect, a series of fast, continuous channels that run the entire length and width of the device. The I/O pins are supported by I/O cells (IOCs) located at the end of each row (horizontal) and column (vertical) path of the FastTrack Interconnect.

Each LAB is fed by 33 inputs from the row interconnect and 16 feedback signals from the macrocells within the LAB. All of these signals are available within the LAB in their true and inverted form. In addition, 16 shared expander product terms ("expanders") are available in their inverted form, for a total of 114 signals that feed each product term in the LAB. Each LAB is also fed by two low-skew global clocks and one global clear that can be used for register control signals in all 16 macrocells.

LABs drive the row and column interconnect directly. Each macrocell can drive out of the LAB onto one or both routing resources. Once on the row or column interconnect, signals can traverse to other LABs or to the IOCs.

Figure 2. MAX 9000 Logic Array Block



Macrocells

The MAX 9000 macrocell consists of three functional blocks: the product terms, the product-term select matrix, and the programmable register. The macrocell can be individually configured for both sequential and combinatorial logic operation. See Figure 3.

LAB Local Array Global Global 33 Row Clear Clocks FastTrack Parallel Interconnect 2 Expanders Inputs Macrocell Register Programmable (from Other Input Select Bypass Register Macrocells) To Row or Column FastTrack Clock/ Interconnect Product-(11) Enable ENA Select Select Matrix Clear Select 1 Local Array Feedback 16 Local 16 Shareable Feedbacks Expander Product

Figure 3. MAX 9000 Macrocell & Local Array

Combinatorial logic is implemented in the local array, which provides five product terms per macrocell. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the \mbox{OR} and \mbox{MOR} gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register clear, preset, clock, and clock enable control functions. Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The MAX+PLUS II software automatically optimizes product-term allocation according to the logic requirements of the design.

For registered functions, each macrocell register can be individually programmed for D, T, JK, or SR operation with programmable clock control. The flipflop can also be bypassed for combinatorial operation. During design entry, the user specifies the desired register type; the MAX+PLUS II software then selects the most efficient register operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- By either global clock signal. This mode achieves the fastest clock-tooutput performance.
- By a global clock signal and enabled by an active-high clock enable. This mode provides an enable on each flipflop while still achieving the fast clock-to-output performance of the global clock.
- By an array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

Two global clock signals are available. As shown in Figure 2, these global clock signals can be the true or the complement of either of the global clock pins (DIN1 and DIN2).

Each register also supports asynchronous preset and clear functions. As shown in Figure 3, the product-term select matrix allocates product terms to control these operations. Although the product-term-driven preset and clear inputs to registers are active high, active-low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the dedicated global clear pin (DIN3). The global clear can be programmed for active-high or active-low operation.

All MAX 9000 macrocells offer a dual-output structure that provides independent register and combinatorial logic output within the same macrocell. This function is implemented by a process called register packing. When register packing is used, the product-term select matrix allocates one product term to the D input of the register, while the remaining product terms can be used to implement unrelated combinatorial logic. Both the registered and the combinatorial output of the macrocell can feed either the FastTrack Interconnect or the LAB local array.

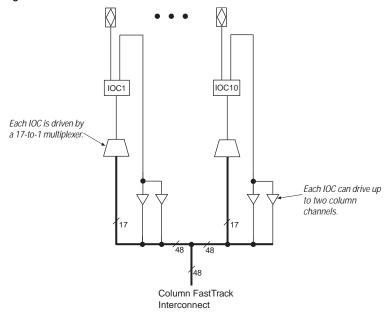


Figure 9. MAX 9000 Column-to-IOC Connections

Dedicated Inputs

In addition to the general-purpose I/O pins, MAX 9000 devices have four dedicated input pins. These dedicated inputs provide low-skew, device-wide signal distribution to the LABs and IOCs in the device, and are typically used for global clock, clear, and output enable control signals. The global control signals can feed the macrocell or IOC clock and clear inputs, as well as the IOC output enable. The dedicated inputs can also be used as general-purpose data inputs because they can feed the row FastTrack Interconnect (see Figure 2 on page 7).

I/O Cells

Figure 10 shows the IOC block diagram. Signals enter the MAX 9000 device from either the I/O pins that provide general-purpose input capability or from the four dedicated inputs. The IOCs are located at the ends of the row and column interconnect channels.

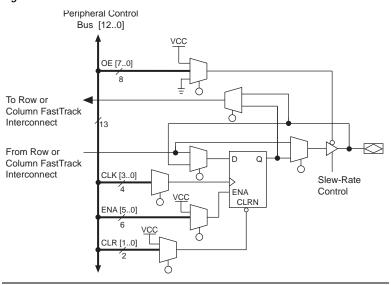


Figure 10. MAX 9000 IOC

I/O pins can be used as input, output, or bidirectional pins. Each IOC has an IOC register with a clock enable input. This register can be used either as an input register for external data that requires fast setup times, or as an output register for data that requires fast clock-to-output performance. The IOC register clock enable allows the global clock to be used for fast clock-to-output performance, while maintaining the flexibility required for selective clocking.

The clock, clock enable, clear, and output enable controls for the IOCs are provided by a network of I/O control signals. These signals can be supplied by either the dedicated input pins or internal logic. The IOC control-signal paths are designed to minimize the skew across the device. All control-signal sources are buffered onto high-speed drivers that drive the signals around the periphery of the device. This "peripheral bus" can be configured to provide up to eight output enable signals, up to four clock signals, up to six clock enable signals, and up to two clear signals. Table 6 on page 18 shows the sources that drive the peripheral bus and how the IOC control signals share the peripheral bus.

The programming times described in Tables 7 through 9 are associated with the worst-case method using the ISP algorithm.

Table 7. MAX 9000 t _{PULSE} & Cycle _{TCK} Values								
Device	Progra	ımming	Stand-Alone Verification					
	t _{PPULSE} (s)	Cycle _{PTCK}	t _{VPULSE} (s)	Cycle _{VTCK}				
EPM9320 EPM9320A	11.79	2,966,000	0.15	1,806,000				
EPM9400	12.00	3,365,000	0.15	2,090,000				
EPM9480	12.21	3,764,000	0.15	2,374,000				
EPM9560 EPM9560A	12.42	4,164,000	0.15	2,658,000				

Tables 8 and 9 show the in-system programming and stand alone verification times for several common test clock frequencies.

Table 8. MAX 9000 In-System Programming Times for Different Test Clock Frequencies										
Device				f	TCK				Units	
	10 MHz	Hz 5 MHz 2 MHz 1 MHz 500 kHz 200 kHz 100 kHz 50 kHz								
EPM9320 EPM9320A	12.09	12.38	13.27	14.76	17.72	26.62	41.45	71.11	S	
EPM9400	12.34	12.67	13.68	15.37	18.73	28.83	45.65	79.30	S	
EPM9480	12.59	12.96	14.09	15.98	19.74	31.03	49.85	87.49	S	
EPM9560 EPM9560A	12.84	13.26	14.50	16.59	20.75	33.24	54.06	95.70	S	

Table 9. MAX 9000 Stand-Alone Verification Times for Different Test Clock Frequencies										
Device				f	TCK				Units	
	10 MHz	Hz 5 MHz 2 MHz 1 MHz 500 kHz 200 kHz 100 kHz 50 kHz								
EPM9320 EPM9320A	0.33	0.52	1.06	1.96	3.77	9.18	18.21	36.27	S	
EPM9400	0.36	0.57	1.20	2.24	4.33	10.60	21.05	41.95	S	
EPM9480	0.39	0.63	1.34	2.53	4.90	12.02	23.89	47.63	S	
EPM9560 EPM9560A	0.42	0.69	1.48	2.81	5.47	13.44	26.73	53.31	S	

Programming with External Hardware

MAX 9000 devices can be programmed on Windows-based PCs with an Altera Logic Programmer card, the Master Programming Unit (MPU), and the appropriate device adapter. The MPU performs continuity checking to ensure adequate electrical contact between the adapter and the device.



For more information, see the Altera Programming Hardware Data Sheet.

The MAX+PLUS II software can use text- or waveform-format test vectors created with the MAX+PLUS II Text Editor or Waveform Editor to test a programmed device. For added design verification, designers can perform functional testing to compare the functional behavior of a MAX 9000 device with the results of simulation.

Data I/O, BP Microsystems, and other programming hardware manufacturers also provide programming support for Altera devices.



For more information, see Programming Hardware Manufacturers.

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 9000 devices support JTAG BST circuitry as specified by IEEE Std. 1149.1-1990. Table 10 describes the JTAG instructions supported by the MAX 9000 family. The pin-out tables starting on page 38 show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

Table 10. MAX 9000	O JTAG Instructions
JTAG Instruction	Description
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins.
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation.
IDCODE	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be shifted out of TDO. Supported by the EPM9320A, EPM9400, EPM9480, and EPM9560A devices only.
UESCODE	Selects the user electronic signature (UESCODE) register and allows the UESCODE to be shifted out of TDO serially. This instruction is supported by MAX 9000A devices only.
ISP Instructions	These instructions are used when programming MAX 9000 devices via the JTAG ports with the BitBlaster or ByteBlasterMV download cable, or using a Jam File (.jam), Jam Byte-Code File (.jbc), or Serial Vector Format (.svf) File via an embedded processor or test equipment.

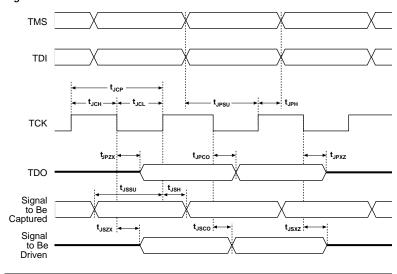


Figure 11. MAX 9000 JTAG Waveforms

Table 13 shows the JTAG timing parameters and values for MAX 9000 devices.

Table 1	3. JTAG Timing Parameters & Values for MAX 90	00 Devi	ices	
Symbol	Parameter	Min	Max	Unit
t _{JCP}	TCK clock period	100		ns
t _{JCH}	TCK clock high time	50		ns
t _{JCL}	TCK clock low time	50		ns
t _{JPSU}	JTAG port setup time	20		ns
t _{JPH}	JTAG port hold time	45		ns
t _{JPCO}	JTAG port clock to output		25	ns
t _{JPZX}	JTAG port high impedance to valid output		25	ns
t _{JPXZ}	JTAG port valid output to high impedance		25	ns
t _{JSSU}	Capture register setup time	20		ns
t _{JSH}	Capture register hold time	45		ns
t _{JSCO}	Update register clock to output		25	ns
t _{JSZX}	Update register high impedance to valid output		25	ns
t _{JSXZ}	Update register valid output to high impedance		25	ns



For detailed information on JTAG operation in MAX 9000 devices, refer to Application Note 39 (IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices).

Operating Conditions

Tables 14 through 20 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for MAX 9000 devices.

Table 1	Table 14. MAX 9000 Device Absolute Maximum Ratings Note (1)									
Symbol	Parameter	Conditions	Min	Max	Unit					
V _{CC}	Supply voltage	With respect to ground (2)	-2.0	7.0	V					
VI	DC input voltage		-2.0	7.0	V					
V _{CCISP}	Supply voltage during in-system programming		-2.0	7.0	V					
I _{OUT}	DC output current, per pin		-25	25	mA					
T _{STG}	Storage temperature	No bias	-65	150	° C					
T _{AMB}	Ambient temperature	Under bias	-65	135	° C					
T_{J}	Junction temperature	Ceramic packages, under bias		150	° C					
		PQFP and RQFP packages, under bias		135	° C					

Table 1	5. MAX 9000 Device Recommend	ed Operating Conditions			
Symbol	Parameter	Conditions	Min	Max	Unit
V _{CCINT}	Supply voltage for internal logic and input buffers	(3), (4)	4.75 (4.50)	5.25 (5.50)	V
V _{CCIO}	Supply voltage for output drivers, 5.0-V operation	(3), (4)	4.75 (4.50)	5.25 (5.50)	٧
	Supply voltage for output drivers, 3.3-V operation	(3), (4)	3.00 (3.00)	3.60 (3.60)	V
V _{CCISP}	Supply voltage during in-system programming		4.75	5.25	V
VI	Input voltage		-0.5	V _{CCINT} + 0.5	٧
Vo	Output voltage		0	V _{CCIO}	V
T _A	Ambient temperature	For commercial use	0	70	° C
		For industrial use	-40	85	° C
T _J	Junction temperature	For commercial use	0	90	° C
		For industrial use	-40	105	° C
t _R	Input rise time			40	ns
t _F	Input fall time			40	ns

Tables 21 through 24 show timing for MAX 9000 devices.

Symbol	Parameter Conditions				Speed	Grade			Unit	
			Ţ		10	-1	5	-2	20	•
				Min	Max	Min	Max	Min	Max	
t _{PD1}	Row I/O pin input to row I/O pin output	C1 = 35 pF	C1 = 35 pF (2)		10.0		15.0		20.0	ns
t _{PD2} Column I/O pin input to		C1 = 35 pF	EPM9320A		10.8					ns
	column I/O pin output	(2)	EPM9320				16.0		23.0	ns
			EPM9400				16.2		23.2	ns
			EPM9480				16.4		23.4	ns
			EPM9560A		11.4					ns
			EPM9560				16.6		23.6	ns
t _{FSU}	Global clock setup time for I/O cell			3.0		5.0		6.0		ns
t _{FH}	Global clock hold time for I/O cell			0.0		0.0		0.0		ns
t _{FCO}	Global clock to I/O cell output delay	C1 = 35 pF		1.0 (3)	4.8	1.0 (3)	7.0	1.0 (3)	8.5	ns
t _{CNT}	Minimum internal global clock period	(4)			6.9		8.5		10.0	ns
f _{CNT}	Maximum internal global clock frequency	(4)		144.9		117.6		100.0		MHz

Table 22	2. MAX 9000 Internal Tim	ing Characteristics	Note (1)						
Symbol	Parameter	Conditions		Speed Grade					
				-10 -15 -20		-20			
			Min	Max	Min	Max	Min	Max	
t_{LAD}	Logic array delay			3.5		4.0		4.5	ns
t _{LAC}	Logic control array delay			3.5		4.0		4.5	ns
t _{IC}	Array clock delay			3.5		4.0		4.5	ns
t _{EN}	Register enable time			3.5		4.0		4.5	ns
t _{SEXP}	Shared expander delay			3.5		5.0		7.5	ns
t _{PEXP}	Parallel expander delay			0.5		1.0		2.0	ns
t _{RD}	Register delay			0.5		1.0		1.0	ns
t _{COMB}	Combinatorial delay			0.4		1.0		1.0	ns
t _{SU}	Register setup time		2.4		3.0		4.0		ns
t _H	Register hold time		2.0		3.5		4.5		ns
t _{PRE}	Register preset time			3.5		4.0		4.5	ns
t _{CLR}	Register clear time			3.7		4.0		4.5	ns
t _{FTD}	FastTrack drive delay			0.5		1.0		2.0	ns
t_{LPA}	Low-power adder	(5)		10.0		15.0		20.0	ns

Table 23. IOC Delays									
Symbol	Parameter	Conditions	Speed Grade					Unit	
			-10		-15		-20		
			Min	Max	Min	Max	Min	Max	
t _{IODR}	I/O row output data delay			0.2		0.2		1.5	ns
t _{IODC}	I/O column output data delay			0.4		0.2		1.5	ns
t _{IOC}	I/O control delay	(6)		0.5		1.0		2.0	ns
t _{IORD}	I/O register clock-to-output delay			0.6		1.0		1.5	ns
t _{IOCOMB}	I/O combinatorial delay			0.2		1.0		1.5	ns
t _{IOSU}	I/O register setup time before clock		2.0		4.0		5.0		ns
t _{IOH}	I/O register hold time after clock		1.0		1.0		1.0		ns
t _{IOCLR}	I/O register clear delay			1.5		3.0		3.0	ns
t _{IOFD}	I/O register feedback delay			0.0		0.0		0.5	ns
t _{INREG}	I/O input pad and buffer to I/O register delay			3.5		4.5		5.5	ns
t _{INCOMB}	I/O input pad and buffer to row and column delay			1.5		2.0		2.5	ns
t _{OD1}	Output buffer and pad delay, Slow slew rate = off, V _{CCIO} = 5.0 V	C1 = 35 pF		1.8		2.5		2.5	ns
t _{OD2}	Output buffer and pad delay, Slow slew rate = off, V _{CCIO} = 3.3 V	C1 = 35 pF		2.3		3.5		3.5	ns
t _{OD3}	Output buffer and pad delay, Slow slew rate = on, V _{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF		8.3		10.0		10.5	ns
t_{XZ}	Output buffer disable delay	C1 = 5 pF		2.5		2.5		2.5	ns
t _{ZX1}	Output buffer enable delay, Slow slew rate = off, V _{CCIO} = 5.0 V	C1 = 35 pF		2.5		2.5		2.5	ns
t _{ZX2}	Output buffer enable delay, Slow slew rate = off, V _{CCIO} = 3.3 V	C1 = 35 pF		3.0		3.5		3.5	ns
t_{ZX3}	Output buffer enable delay, Slow slew rate = on, V _{CCIO} = 3.3 V or 5.0 V	C1 = 35 pF		9.0		10.0		10.5	ns

The parameters in this equation are shown below:

MC_{TON} = Number of macrocells with the Turbo Bit option turned on, as reported in the MAX+PLUS II Report File (.rpt)

 MC_{DEV} = Number of macrocells in the device

 $MC_{USED} = Number of macrocells used in the design, as reported in the MAX+PLUS II Report File$

f_{MAX} = Highest clock frequency to the device

 tog_{LC} = Average percentage of logic cells toggling at each clock

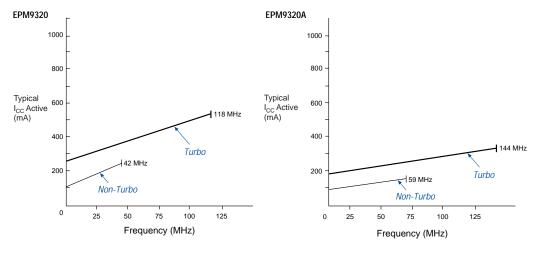
(typically 12.5%)

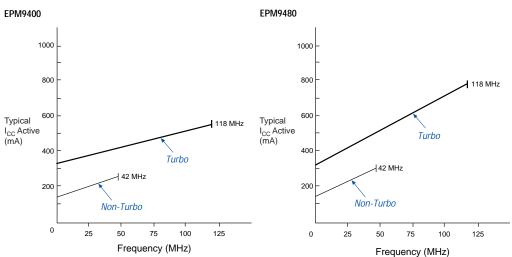
A, B, C = Constants, shown in Table 25

Table 25. MAX 9000 I _{CC} Equation Constants				
Device	Constant A	Constant B	Constant C	
EPM9320	0.81	0.33	0.056	
EPM9320A	0.56	0.31	0.024	
EPM9400	0.60	0.33	0.053	
EPM9480	0.68	0.29	0.064	
EPM9560	0.68	0.26	0.052	
EPM9560A	0.56	0.31	0.024	

This calculation provides an $I_{\rm CC}$ estimate based on typical conditions with no output load, using a typical pattern of a 16-bit, loadable, enabled up/down counter in each LAB. Actual $I_{\rm CC}$ values should be verified during operation, because the measurement is sensitive to the actual pattern in the device and the environmental operating conditions. Figure 15 shows typical supply current versus frequency for MAX 9000 devices.







Notes:

- (1) All pins not listed are user I/O pins.
- (2) Perform a complete thermal analysis before committing a design to this device package. See Application Note 74 (Evaluating Power for Altera Devices).
- (3) EPM9320A devices are not offered in this package.
- (4) During in-system programming, each device's VPP pin must be connected to the 5.0-V power supply. During normal device operation, the VPP pin is pulled up internally and can be connected to the 5.0-V supply or left unconnected.
- (5) The user I/O pin count includes dedicated input pins and all I/O pins.

Table 27. EPM9400 Ded	licated Pin-Outs Note (1)		
Pin Name	84-Pin PLCC (2)	208-Pin RQFP	240-Pin RQFP
DIN1 (GCLK1)	2	182	210
DIN2 (GCLK2)	1	183	211
DIN3 (GCLR)	12	153	187
DIN4 (GOE)	74	4	234
TCK	43	78	91
TMS	54	49	68
TDI	42	79	92
TDO	31	108	114
GND	6, 13, 20, 26, 27, 47, 60, 66, 69, 73	14, 20, 24, 31, 35, 41, 42, 43, 44, 46, 47, 66, 85, 102, 110, 113, 114, 115, 116, 118, 121, 122, 132, 133, 143, 152, 170, 189, 206	5, 14, 25, 34, 45, 54, 65, 66, 81, 96, 110, 115, 126, 127, 146, 147, 166, 167, 186, 200, 216, 229
VCCINT (5.0 V only)	16, 23, 30, 56, 63, 70	10, 19, 30, 45, 112, 128, 139, 148	4, 24, 44, 64, 117, 137, 157, 177
VCCIO (3.3 or 5.0 V)	17, 37, 59, 80	5, 25, 36, 55, 72, 91, 111, 127, 138, 159, 176, 195	15, 35, 55, 73, 86, 101, 116, 136, 156, 176, 192, 205, 220, 235
No Connect (N.C.)	_	6, 7, 8, 9, 11, 12, 13, 109, 144, 145, 146, 147, 149, 150, 151	1, 2, 3, 6, 7, 8, 9, 10, 11, 12, 13, 168, 169, 170, 171, 172, 173, 174, 175, 178, 179, 180, 181, 182, 183, 184, 185, 236, 237, 238, 239, 240
VPP (3)	55	48	67
Total User I/O Pins (4)	59	139	159

Notes:

- (1) All pins not listed are user I/O pins.
- (2) Perform a complete thermal analysis before committing a design to this device package. See *Application Note 74* (Evaluating Power for Altera Devices) for more information.
- (3) During in-system programming, each device's VPP pin must be connected to the 5.0-V power supply. During normal device operation, the VPP pin is pulled up internally and can be connected to the 5.0-V supply or left unconnected.
- (4) The user I/O pin count includes dedicated input pins and all I/O pins.

Table 28. EPM9480 Dedicated Pin-Outs Note (1)				
Pin Name	208-Pin RQFP	240-Pin RQFP		
DIN1 (GCLK1)	182	210		
DIN2 (GCLK2)	183	211		
DIN3 (GCLR)	153	187		
DIN4 (GOE)	4	234		
TCK	78	91		
TMS	49	68		
TDI	79	92		
TDO	108	114		
GND	14, 20, 24, 31, 35, 41, 42, 43, 44, 46, 47, 66, 85, 102, 110, 113, 114, 115, 116, 118, 121, 122, 132, 133, 143, 152, 170, 189, 206	5, 14, 25, 34, 45, 54, 65, 66, 81, 96, 110, 115, 126, 127, 146, 147, 166, 167, 186, 200, 216, 229		
VCCINT (5.0 V only)	10, 19, 30, 45, 112, 128, 139, 148	4, 24, 44, 64, 117, 137, 157, 177		
VCCIO (3.3 or 5.0 V)	5, 25, 36, 55, 72, 91, 111, 127, 138, 159, 176, 195	15, 35, 55, 73, 86, 101, 116, 136, 156, 176, 192, 205, 220, 235		
No Connect (N.C.)	6, 7, 8, 9, 109, 149, 150, 151	1, 2, 3, 178, 179, 180, 181, 182, 183, 184, 185, 236, 237, 238, 239, 240		
VPP (2)	48	67		
Total User I/O Pins (3)	146	175		

Notes:

- (1) All pins not listed are user I/O pins.
- (2) During in-system programming, each device's VPP pin must be connected to the 5.0-V power supply. During normal device operation, the VPP pin is pulled up internally and can be connected to the 5.0-V supply or left unconnected.
- (3) The user I/O pin count includes dedicated input pins and all I/O pins.